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(71) Applicant: MATSUSHITA ELECTRIC IND CO LTD

(72) Inventor: TAKEOKA SADAMI
MOTOHARA AKIRA

(54) INTEGRATED CIRCUIT INSPECTING METHOD

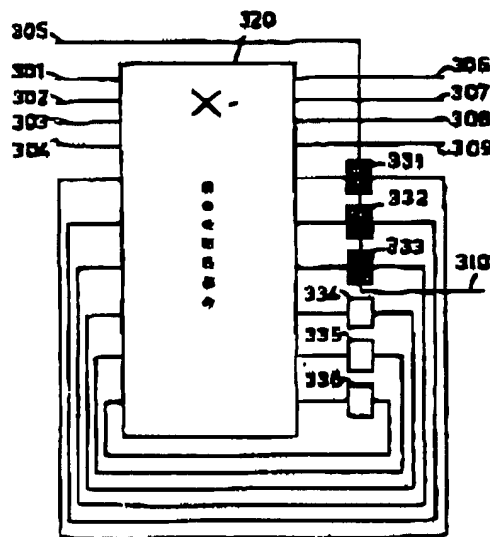
(57) Abstract

PURPOSE: To shorten the inspection input system by effectively using the condition value of a hard-to-set memory element in the circuit condition required for sensing a failure in the process to give an inspection input of a sequence circuit to an external input.

CONSTITUTION: The values of external inputs 301-304 and the condition values of scan memory elements 331-333 can be set to any request values, while it is difficult to set the condition values of memory elements 334-336 to the request values. In the process to give the inspection inputs V1-Vn of a sequence circuit to the inputs 301-304, therefore, attention is paid to the condition values of the elements 334-336, and the condition values of the elements 334-336 when the inspection input V3 is fed to the inputs 301-303 become (1, 0, 1) to be identical to the condition values of the elements 334-336 which are required for a failure α to be sensed. Accordingly changing-over into the scan mode is made after entry of the inputs V1-V3, and (1, 0, 1, 0) is given to the inputs 301-304, and when scan is performed as input 305, the condition values of the

elements 331-336 vary, and affection of the failure α reaches the element 332.

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